## **APPENDIX E: TEST SEQUENCES**

- 1. Test sequence is generated based on below parameters of the DUT:
  - a. Measured maximum power (P<sub>max</sub>)
  - b. Measured Tx\_power\_at\_SAR\_design\_target (Plimit)
  - c. Reserve\_power\_margin (dB)
    - P<sub>reserve</sub> (dBm) = measured P<sub>limit</sub> (dBm) Reserve\_power\_margin (dB)
  - d. SAR\_time\_window (100s for FCC)
- 2. Test Sequence 1 Waveform:

Based on the parameters above, the Test Sequence 1 is generated with one transition between high and low Tx powers. Here, high power =  $P_{max}$ ; low power =  $P_{max}/2$ , and the transition occurs after 80 seconds at high power  $P_{max}$ . As long as the power enforcement is taking into effective during one 100s/60s time window, the validation test with this defined test sequence 1 is valid, otherwise, select other radio configuration (band/DSI within the same technology group) having lower  $P_{limit}$  for this test. The Test sequence 1 waveform is shown below:

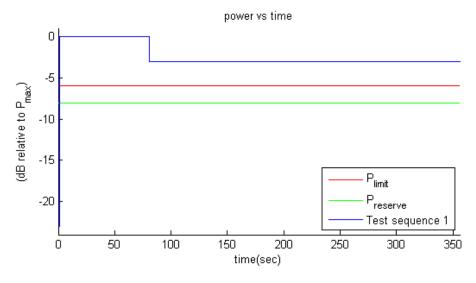


Figure E-1 Test sequence 1 waveform

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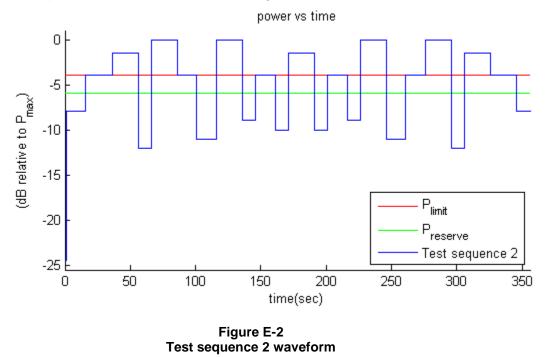
## 3. Test Sequence 2 Waveform:

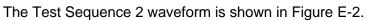
Based on the parameters described above, the Test Sequence 2 is generated as described in Table 10-1, which contains two 170 second-long sequences (yellow and green highlighted rows) that are mirrored around the center row of 20s, resulting in a total duration of 360 seconds:

Time duration (seconds)	dB relative to <i>P<sub>limit</sub></i> or <i>P<sub>reserve</sub></i>	
<mark>15</mark>	P <sub>reserve</sub> – 2	
20	P <sub>limit</sub>	
20	( <i>P<sub>limit</sub></i> + <i>P<sub>max</sub>)/</i> 2 averaged in mW and rounded to nearest 0.1 dB step	
<mark>10</mark>	P <sub>reserve</sub> – 6	
<mark>20</mark>	P <sub>max</sub>	
<mark>15</mark>	P <sub>limit</sub>	
<mark>15</mark>	P <sub>reserve</sub> – 5	
20	P <sub>max</sub>	
<mark>10</mark>	P <sub>reserve</sub> – 3	
<mark>15</mark>	P <sub>limit</sub>	
<mark>10</mark>	P <sub>reserve</sub> – 4	
20	$(P_{limit} + P_{max})/2$ averaged in mW and rounded to nearest 0.1 dB step	
10	P <sub>reserve</sub> – 4	
<mark>15</mark>	P <sub>limit</sub>	
<mark>10</mark>	P <sub>reserve</sub> – 3	
20	P <sub>max</sub>	
<mark>15</mark>	P <sub>reserve</sub> – 5	
<mark>15</mark>	P <sub>limit</sub>	
20	P <sub>max</sub>	
<mark>10</mark>	P <sub>reserve</sub> – 6	
20	$(P_{limit} + P_{max})/2$ averaged in mW and rounded to nearest 0.1 dB step	
20	P <sub>iimit</sub>	
<mark>15</mark>	P <sub>reserve</sub> – 2	

Table E-1 Test Sequence 2

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